

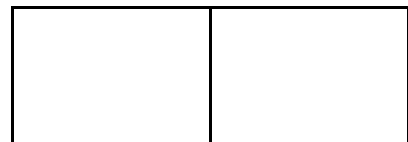
# SPECIFICATIONS

Messrs.

Approved by

|                         |                  |
|-------------------------|------------------|
| Product                 | CRYSTAL UNIT     |
| Type of Holder          | CFS-206          |
| Nominal Frequency       | 32.768 kHz       |
| Customer's Parts Number |                  |
| Our Parts Number        | CFS-20632768EZFB |

Sales CITIZEN FINETECH MIYOTA Co.,LTD. Crystal Devices Department.  
Manufacturer 4107-5,MIYOTA,MIYOTA-MACHI,KITASAKU-GUN,NAGANO,389-0295,JAPAN  
TEL : +81-267-31-1111  
FAX : +81-267-31-1129





## 1. Scope

This document contains specifications for the crystal unit to be supplied by CITIZEN FINETECH MIYOTA Co.,LTD.

- 1.1 If something defined ambiguously or undefined in document happened, the customer and CITIZEN FINETECH MIYOTA would discuss and take necessary steps by mutual consent.
- 1.2 Product test data can't be attached to this document.  
The contents except Electrical Specifications in specifications are subject the change without notice.
- 1.3 This product is not authorized for use as a critical component in life support devices or systems.

## 2. Electrical Specifications

|   |   |
|---|---|
| 2.1 Nominal Frequency                                       | 32.768 kHz  |
| 2.2 Operating Temperature Range                             | -20~+70°C   |
| 2.3 Storage Temperature Range                               | -40~+85°C   |
| 2.4 Frequency Tolerance                                     | ±10ppm Max. at 25°C   |
| 2.5 Frequency Tolerance over<br>Operating Temperature Range | Turnover Temp.; 25±5°C<br>Temp.Coefficient: -0.034±0.006ppm/°C <sup>2</sup> |
| 2.6 Equivalent Series Resistance                            | 35kΩ Max.at 25°C  |
| 2.7 Insulation Resistance                                   | 500MΩ Min./DC100V±15V   |
| 2.8 Shunt Capacitance                                       | 1.20pF Typ.   |

## 3. Test Conditions

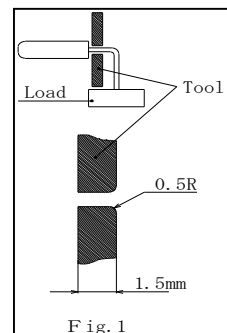
|                      |   |
|----------------------|---|
| 3.1 Load Capacitance | 12.5pF<br>This Load Capacitance has been fixed on customer's request. |
| 3.2 Level of Drive   | 1μW Max.  |

#### 4. Mechanical and Environmental Tests

| Test Name              | Test Conditions              | Criteria No.  |     |
|------------------------|------------------------------|---|-----|
| 1. Mechanical Tests    |                              |   |     |
| 1-1                    | Shock                        | Drop 3 times from the height of 75 cm onto hard wooden board with thickness of 3 cm.  | A   |
| 1-2                    | Vibration                    | Vibration Frequency : 10~500 Hz, 1.5mm, full wave, or acceleration 10G,<br>Cycle : 1.5 minutes, Direction : X.Y.Z.<br>Time : 2 hours in each direction, for 6 hours in total. | A   |
| 1-3                    | Lead Pull                    | Weight : 1.0kg , Time : 30±5 seconds.   | A•C |
| 1-4                    | Bending strength             | Weight : 0.5kg , Bending Angle : 90 degrees, Bending Count : 2 times. (See Fig.1)   | A•C |
| 1-5                    | Solderability                | After applying RMA flux, dip in solder. Dipping Time : 5±0.5seconds.<br>Soldering Temperature : 230±5 °C.<br>Dipping Depth : 2 mm from the edge of terminals of samples.      | D   |
| 1-6                    | Resistance to Soldering Heat | Dip in solder. Dipping Time : 10±0.5 seconds.<br>Soldering Temperature : 260±5 °C.<br>Dipping Depth : 2mm from the edge of lead-wires of samples                              | B   |
| 1-7                    | Sealing Tightness            | Leak rate shall be measured by using Helium Leak Detector.  | E   |
| 2. Environmental Tests |                              |   |     |
| 2-1                    | Storage In Low Temperature   | Expose the sample in an inoperative mode to 240 hours at -40°C.   | A   |
| 2-2                    | Storage In High Temperature  | Expose the sample in an inoperative mode to 240 hours at +85°C.   | B   |
| 2-3                    | Humidity                     | Expose the sample in an inoperative mode to 240 hours at +65°C, and 95%RH.  | B   |
| 2-4                    | Thermal Shock                | Subject the sample to 5 temperature variation cycles at -40°C for 30 minutes and +100°C for the next 30 minutes in each cycle.  | A   |

#### Criteria

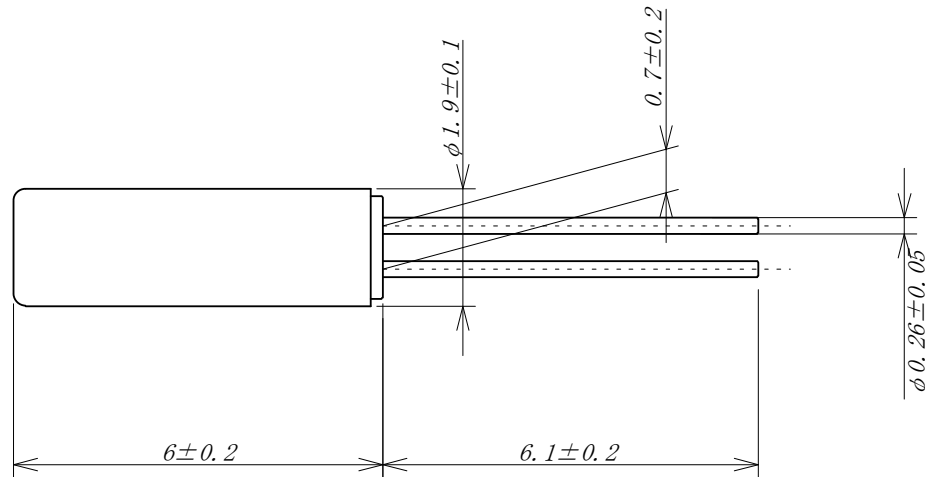
| Criteria No. | Criteria  |
|--------------|---|
| A            | Any variation between the pre- and post-test frequencies shall remain within ±5ppm. The equivalent series resistance shall remain within its specified tolerance range after the post-test.   |
| B            | Any variation between the pre- and post-test frequencies shall remain within ±10ppm. The equivalent series resistance shall remain within its specified tolerance range, after the post-test. |
| C            | After each test, no visible damage, nor the hermetic seal break down.   |
| D            | At least 90% of each dipped area shall be covered by fresh solder.  |
| E            | $1 \times 10^{-2} \mu\text{Pa} \cdot \text{m}^3/\text{s}$ Max.  |



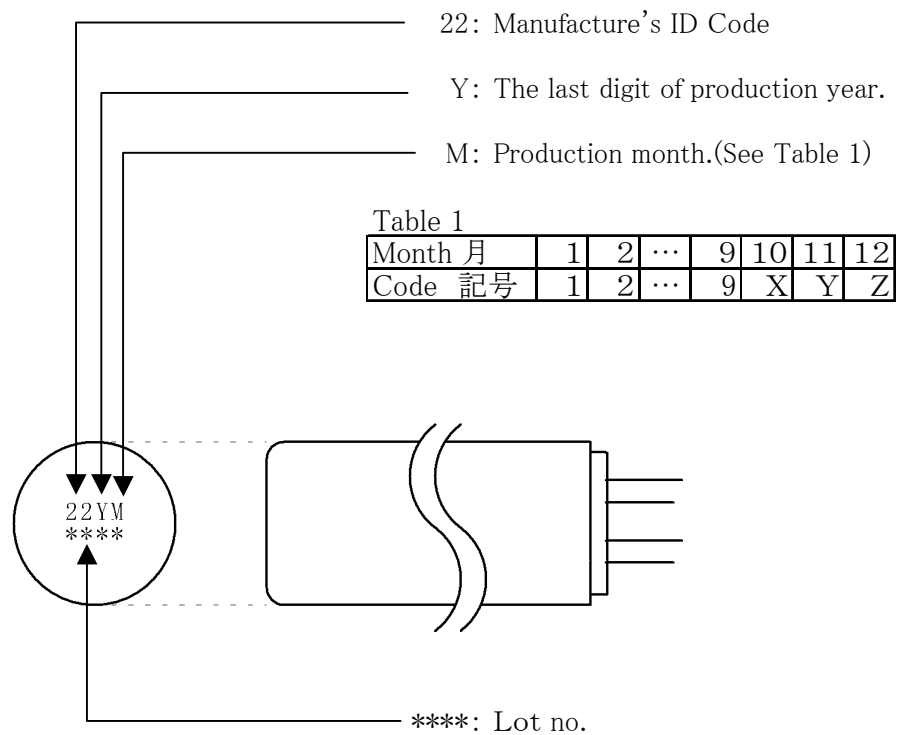
※ Measurements should be taken place at 25±2°C after each test, the samples shall be left at 25°C for one to two hours.

## 5. Dimensions

(unit:mm)



## 6. Marking Standards



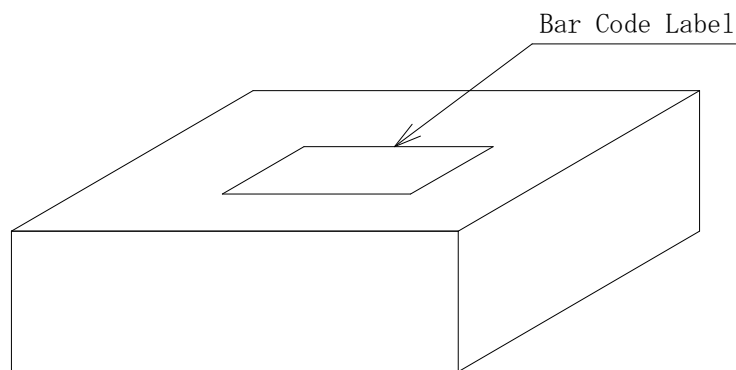
## 7. Packing

### (1) Inner Carton

#### 【Bar Code Label Item】

- \* Customer P/N
- \* Lot.No.
- \* CITIZEN P/N
- \* Ctl No
- \* Date Code      yy : The last 2 digits of shipment year  
                         ww : Week Code
- \* Quantity
- \* Country Code    CN=China

#### 【Inner Carton for 10000pcs】



### (2) Quantity

1000pcs/bag at max. 10000pcs/carton (10 bags)

## 8. Storage Condition

|                           |               |        |
|---------------------------|---------------|--------|
| 8.1 Storage Condition     | Temperature   | 5~35°C |
|                           | Humidity      | 45~75% |
| 8.2 A period of guarantee | Twelve months |        |

## 9. Manufacturer

MASTER CROWN ELECTRONICS (WUZHOU) LIMITED.  
No3 BUILDING 137.XINXING ER ROAD, WUZHOU, GUANGXI, CHINA  
TEL : +86-774-3863148

Country of Origin : CHINA

\* This manufacture is under the control of CITIZEN FINETECH MIYOTA CO.,LTD.

## 10. Ozone Depleting Substance (ODS)

This Product doesn't use the class I ODS at any of production processes, and component parts.

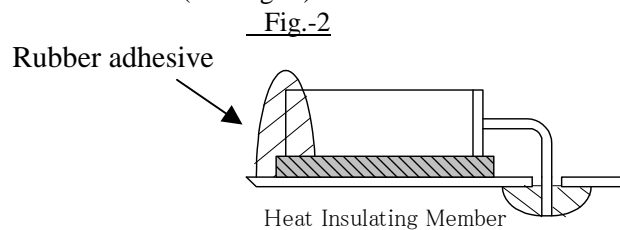
## 11. Precautionary Statement

### 11-1 When dropped by mistake

The crystal products are designed and manufactured to resist physical shocks. However, in the event the crystal is subjected to excessive impact such as being dropped onto the floor or giving shocks during mounting. Need to make sure its satisfactory performance before using it.

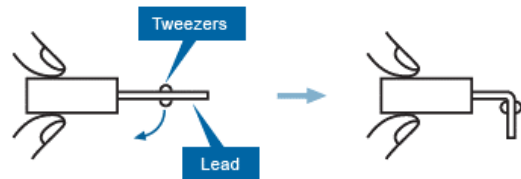
### 11-2 Soldering and Mounting

- (1) Lead wires should be soldered within 3 seconds with the iron heated to a temperature no higher than 380degC.
- (2) In solder-dip mounting, it should be within 10 seconds with a temperature no higher than 260degC.  
And beware not to heat the whole crystal unit in the dip mounting process.  
Mounting in upright bearing is recommendable (prevent heat conduction directly to the body of a crystal unit.)  
(Such as by isolating the unit body from the board with a heat insulating member, see Fig.2.)
- (3) Soldering on the body of the cylinder type crystal unit must be strictly avoided due to deteriorate the characteristics or damage the products.  
Rubber adhesive is recommended. (See Fig.-2)



- (4) Heating the whole crystal unit, for example, in a reflow oven may deteriorate the performance. Because the holder is quite small and it is sealed by solder material with press sealing so that such reflow process not allowed to be proceeded.

- (5) Please (3.0mm recommendation) separate, and bend it as much as possible with a treatment device when it lays in the substrate of the crystal oscillator and it installs it. Please avoid bending it directly from the lead wire root.
- (6) Please do not shave off the solder plating of the lead wire when you bend the lead wire of the crystal oscillator.
- (7) Lead forming by hand when you do the following please
  - \* Hand with a sealed tube
  - \* With fine forceps and bending.
  - 0.5mm position is bending over, bent by hand and if you get into that work, with minimal possible that the 3.0mm hermetically recommended that bend over the place.
  - \* 90 degree bend while holding the lead with tweezers.
  - At this time, please note that you do not have enough pull to lead.



### 11-3 Cleaning

- (1) Crystal products may be affected and destroyed at worst by ultrasonic cleaning. Please be sure to check if your cleaning process affects any damage to crystal products prior to use.
- (2) Some kind of cleaning fluid may cause any damage to crystal products . Please be sure to check suitability of the cleaning fluid in advance.

### 11-4 Storage

Storage of Crystal products under higher temperature or high humidity for a long term may affect frequency stability or solderability. Please store the Crystal products under the normal temperature and humidity without exposing to direct sunlight and dew condensation, and avoid the storage of Crystal products for more than 6 months, and mount them as soon as possible after unpacking.

### 11-5 Replacement

If the defect is caused by our company within one year from the delivery time, we provide the replacements with free of charge.



| QC工程図<br>QC Chart   | 水晶振動子 CFS-206/CFV-206<br>Quartz Crystal Unit                                  | 2013年11月11日<br>November-11-2013<br>水晶部 技術課<br>Crystal Devices Div. Production Dept.<br>Product Engineering Section |  |  | 承認<br>Approved  | 審査<br>Checked | 担当<br>Prepared |
|---|---|--|--|--|---|---------------|----------------|
|   |   |  |  |  |   |               |                |
| 工程図<br>Flowchart  | 工程名<br>Process Name   | 管理仕様<br>Control Specifications   |  |  | 記録<br>Record  |               |                |
|   |   | 管理項目<br>Control Item   | 管理規格<br>Control Criteria                         | 抜取<br>Sampling   |   |               |                |
| <pre> graph TD     START([START]) --&gt; 1[1]     1 --&gt; 2[2]     2 --&gt; 3[3]     3 --&gt; 4{4}     4 --&gt; 5[5]     5 --&gt; 6[6]     6 --&gt; 7[7]     7 --&gt; 8{8}     8 --&gt; 9[9]     9 --&gt; 10[10]     10 --&gt; 11[11]     11 --&gt; 12{12}     12 --&gt; 13{13}     13 --&gt; 14[14]     14 --&gt; END([END]) </pre> | 1 受入検査<br>(水晶片)<br>Acceptance<br>Inspection<br>(Crystal Element)              | 仕様<br>Specification  | 納入仕様書<br>Specifications                          | 品質受入<br>検査基準書<br>Quality<br>Acceptance<br>Inspection<br>Standard | 検査表<br>(水晶片)<br>Inspection Sheets<br>(Crystal Element)                        |               |                |
|   | 2 蒸着<br>Evaporation   | 湿度<br>Humidity<br>真空度<br>Pressure<br>トータル膜厚<br>Total Thickness   | 作業指示書<br>Manufacturing<br>Process<br>Instruction | -  | 記録紙<br>Printed Data<br>稼働表<br>Operating Sheets<br>推移グラフ<br>Change Graph       |               |                |
|   | 3 周波数粗調整<br>Frequency Rough<br>Tuning   | 周波数<br>Frequency<br>外観<br>Appearance   | 作業指示書<br>Manufacturing<br>Process<br>Instruction | 抜取<br>Sampling<br>抜取<br>Sampling                                 | チェックシート<br>Check Sheets<br>送品検査表<br>Process Inspection<br>Sheets              |               |                |
|   | 4 受入検査<br>(気密端子)<br>Acceptance<br>Inspection<br>(Heametically<br>Sealed Base) | 仕様<br>Specification  | 納入仕様書<br>Specifications                          | 品質受入<br>検査基準書<br>Quality<br>Acceptance<br>Inspection<br>Standard | 検査表<br>Inspection Sheets  |               |                |
|   | 5 組立<br>Assembly  | 外観<br>Appearance   | 作業指示書<br>Manufacturing<br>Process<br>Instruction | 全数<br>100%   | チェックシート<br>Check sheets   |               |                |
|   | 6 周波数微調整<br>Fine Tuning   | 周波数<br>Frequency   | 作業指示書<br>Manufacturing<br>Process<br>Instruction | 抜取<br>Sampling   | 分布図<br>Distribution Chart   |               |                |
|   | 7 アニール<br>(半完成品)<br>Annealing   | 真空度<br>Pressure<br>温度<br>Temperature<br>時間<br>Time   | 作業指示書<br>Manufacturing<br>Process                | -  | チェックシート<br>Check Sheets<br>チェックシート<br>Check Sheets<br>チェックシート<br>Check Sheets |               |                |
|   | 8 受入検査<br>(封止管)<br>Acceptance<br>Inspection<br>(Cap)                          | 仕様<br>Specification  | 納入仕様書<br>Specifications                          | 品質受入<br>検査基準書<br>Quality<br>Acceptance<br>Inspection<br>Standard | 検査表<br>Inspection Sheets  |               |                |
|   | 9 封止<br>Sealing   | 真空度<br>Pressure<br>寸法<br>Dimension   | 作業指示書<br>Manufacturing<br>Process                | 抜取<br>Sampling   | チェックシート<br>Check Sheets<br>Xbar-R管理図<br>Xbar-R Control<br>Chart               |               |                |
|   | 10 印刷<br>Marking  | 印刷外観<br>Marking<br>Appearance  | 作業指示書<br>Manufacturing<br>Process                | 抜取<br>Sampling   | チェックシート<br>Check Sheets   |               |                |
|   | 11 ベーキング<br>Baking  | 温度<br>Temperature<br>時間<br>Time  | 作業指示書<br>Manufacturing<br>Process<br>Instruction | -  | チェックシート<br>Check Sheets<br>作業履歴票<br>Manufacturing<br>Record                   |               |                |
|   | 12 電気特性検査<br>Electrical<br>Characteristics<br>Inspection                      | 電気的特性<br>Electrical<br>Characteristics   | 作業指示書<br>Manufacturing<br>Process<br>Instruction | 全数<br>100%   | チェックシート<br>Check Sheets   |               |                |
|   | 13 出荷判定<br>Delivery<br>Judgment   | 電気的特性<br>Electrical<br>Characteristics   | 出荷判定基準書<br>Delivery<br>Judgment<br>Standard      | 抜取<br>Sampling   | 出荷判定成績表<br>Delivery<br>Judgment Sheets  |               |                |
|   | 14 梱包<br>Packing  | 個数<br>Quantity   | 梱包仕様書<br>Packing<br>Specification                | -  | -   |               |                |